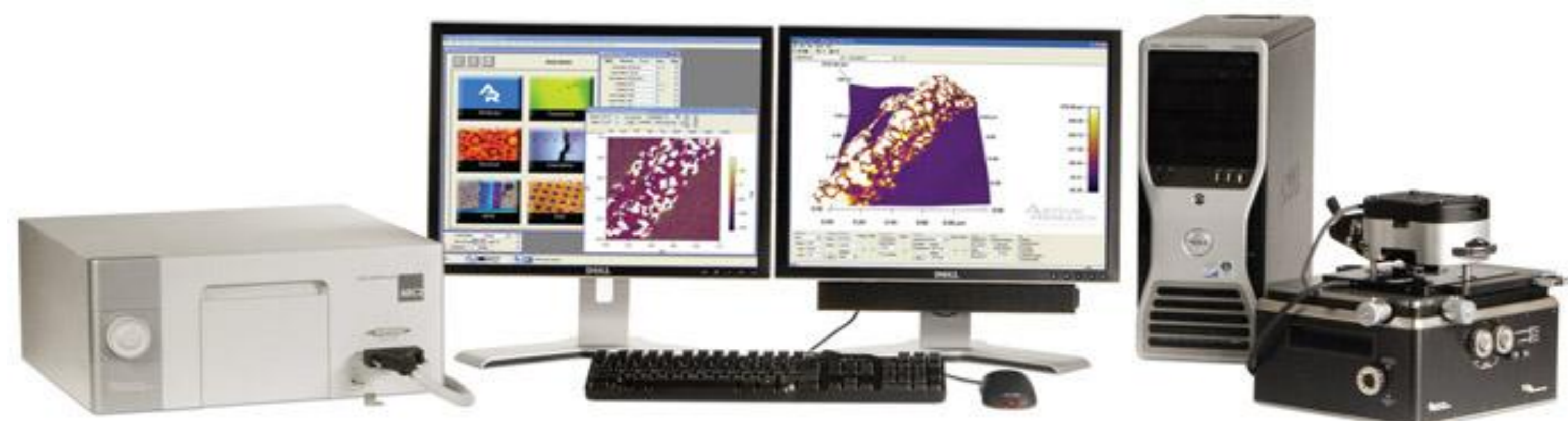




扫描探针（原子力）显微镜

MFP-3D-SA



原子力显微镜（AFM）已经成为纳米尺度上进行三维测量的首选设备。可以为科研工作者提供最优的噪声性能和完整的科学分析软件环境，同时保证实验具有高灵敏度和精确性。在众多应用中，包括物理学、材料科学、高分子、化学、纳米刻蚀、生物学和定量纳米测量，AFM都是非常理想的设备。

The Atomic Force Microscope (AFM), has been the instrument of choice for three dimensional measurements at the nanometer scale. The MFP-3D-SA is ideal for many applications including physics, material science, polymers, chemistry, nanolithography, bioscience, and quantitative nanoscale measurements.

技术指标 SPECIFICATION

X&Y	90 μ m travel in closed loop. Closed loop position control with sensor noise <0.5nm average deviation (Adev) in a 0.1Hz-1kHz bandwidth (BW) and sensor nonlinearity <0.05% (Adev/full travel) at full scan.
Z	>15 μ m sensed travel. Sensor noise <0.25nm Adev in a 0.1Hz-1kHz BW and sensor non-linearity less than 0.05% (Adev/full travel) at full scan
Z height	noise <0.06nm Adev, 0.1Hz-1kHz BW
Stage	Micrometer driven
CCD	720 μ m and 240 μ m fields of view; Top view resolution:3 μ m
Optical Lever Noise	<0.02nm Adev in a 0.1Hz to 1kHz BW.
Controller	Frequency: DC to 2.0MHz in 2mHz increments Amplitude: 0 to 20V(p-p) in 0.6mV increments